

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Leonard Forbes Examiner:

Joannie A. Garcia

Group Art Unit: 2

2823

Docket:

1303.102US1

Title:

No.:

August 05, 2003

10/634,174

STRAINED Si/SiGe/SOI ISLANDS AND PROCESSES OF MAKING SAME

INFORMATION DISCLOSURE STATEMENT

MS RCE Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

In compliance with the duty imposed by 37 C.F.R. § 1.56, and in accordance with 37 C.F.R. §§ 1.97 et. seq., the enclosed materials are brought to the attention of the Examiner for consideration in connection with the above-identified patent application. Applicant respectfully requests that this Information Disclosure Statement be entered and the documents listed on the attached Form 1449 be considered by the Examiner and made of record. Pursuant to the provisions of MPEP 609, Applicant requests that a copy of the 1449 form, initialed as being considered by the Examiner, be returned to the Applicant with the next official communication.

Pursuant to 37 C.F.R. §1.97(b), it is believed that no fee or statement is required with the Information Disclosure Statement. However, the Commissioner is hereby authorized to charge the required fees to Deposit Account No. 19-0743 in order to have this Information Disclosure Statement considered.

Filing Date: August 05, 2003

Title: STRAINED SI/SiGe/SOI ISLANDS AND PROCESSES OF MAKING SAME

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Pursuant to 37 C.F.R. 1.98(a)(2), Applicant believes that copies of cited U.S. Patents and Published Applications are no longer required to be provided to the Office. Notification of this change was provided in the United States Patent and Trademark Office OG Notices dated October 12, 2004. Thus, Applicant has not included copies of any US Patents or Published Applications cited with this submission. Should the Office require copies to be provided, Applicant respectfully requests that notice of such requirement be directed to Applicant's below-signed representative. Applicant acknowledges the requirement to submit copies of foreign patent documents and non-patent literature in accordance with 37 C.F.R. 1.98(a)(2).

The Examiner is invited to contact the Applicant's Representative at the below-listed telephone number if there are any questions regarding this communication.

Respectfully submitted,

LEONARD FORBES

By his Representatives,

SCHWEGMAN, LUNDBERG, WOESSNER & KLUTH, P.A. P.O. Box 2938
Minneapolis, MN 55402
(612) 373-6960

Date 7-19-06

Bv

Marvin L. Beekman

Reg. No. 38,377

CERTIFICATE UNDER 37 CFR 1.8: The undersigned hereby certifies that this correspondence is being deposited with the United States Postal Service with sufficient postage as first class mail, in an envelope addressed to: Mail Stop RCE, Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450 on this ______ day of July 2006.

Signature

Substitute for form 1449A/PTO
INFORMATION DISCLOSURE
STATEMENT BY APPLICANT
We as many sheets as necessary)

Complete if Known

Application Number
Filing Date
First Named Inventor

Group Art Unit

2823

Examiner Name

Attorney Docket No: 1303.102US1

Garcia, Joannie

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EXAMINER DATE CONSIDERED

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Approved for use through 10/31/2002. OMB 651-0031

US Patent & Trademark Office; U.S. DEPARTMENT OF COMMERCE

Under the Paperwork Reduction Act of 1995, no persons are required to respond to a collection of information unless it contains a valid OMB control number. Substitute for form 1449A/PTO Complete if Known INFORMATION DISCLOSURE 10/634,174 **Application Number** STATEMENT BY APPLICANT August 5, 2003 **Filing Date** (Use as many sheets as necessary) **First Named Inventor** Forbes, Leonard 2823 **Group Art Unit** Garcia, Joannie **Examiner Name** Attorney Docket No: 1303.102US1 Sheet 2 of 2

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